

#### **30V N-Channel Enhancement Mode MOSFET**

#### Description

The AP50N03DF uses advanced trench technology

to provide excellent  $R_{\text{DS}(\text{ON})},$  low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

#### **General Features**

V<sub>DS</sub> = 30V I<sub>D</sub> =50A

 $R_{DS(ON)} < 12m\Omega @ V_{GS}=10V$  (Type: 10.5m $\Omega$ )

#### Application

Lithium battery protection

Wireless impact

Mobile phone fast chargin

#### Package Marking and Ordering Information

ØAPM AP50N03DF XXX YYYY	



Product ID	Pack	Marking	Qty(PCS)	
AP50N03DF	PDFN3*3-8L	AP50N03DF XXX YYYY	5000	

#### Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	30	V
VGS	Gate-Source Voltage	±20	V
I⊳@Tc=25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	50	А
I⊳@Tc=100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	23	А
IDM	Pulsed Drain Current <sup>2</sup>	75	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	24.2	mJ
IAS	Avalanche Current	22	A
P₀@T₀=25℃	Total Power Dissipation <sup>4</sup>	26	W
PD@TA=25°C	Total Power Dissipation <sup>4</sup>	1.67	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R₀JA	Thermal Resistance Junction-Ambient <sup>1</sup>	75	°C/W
R₀JC	Thermal Resistance Junction-Case <sup>1</sup>	4.8	°C/W

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#### Electrical Characteristics (Tc=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}$ =0V , I <sub>D</sub> =250uA	30			V
RDS(ON) Static Drain-Source On-Resistance <sup>2</sup>		V <sub>GS</sub> =10V , I <sub>D</sub> =6A		10.5	12	mΩ
(- )	-	V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A		15.5	19	11132
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}$ = $V_{DS}$ , $I_D$ =250uA	1.2	1.6	2.5	V
IDSS Drain-Source Leakage Current		V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	uA
1033	Brain-Bouroe Leakage Burrenk	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , TJ=55℃			5	u, (
lgss	Gate-Source Leakage Current	$V_{\text{GS}}\text{=}\pm20\text{V}$ , $V_{\text{DS}}\text{=}0\text{V}$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =12A		32		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		2.1		Ω
Qg	Total Gate Charge (4.5V)			4.2		
Qgs	Gate-Source Charge	V <sub>DS</sub> =15V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =6A		2.6		nC
Qgd	Gate-Drain Charge			1.4		
Td(on)	Turn-On Delay Time			13.1		
Tr	Rise Time	V <sub>DD</sub> =15V , V <sub>GS</sub> =10V , R <sub>G</sub> =1.5Ω		6.3		
Td(off)	Turn-Off Delay Time	ID=1A		21		ns
Tf	Fall Time			7		
Ciss	Input Capacitance			870		
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		135		pF
Crss	Reverse Transfer Capacitance			87		
ls	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0V$ , Force Current			37	А
Vsd	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1	V

Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

 $3\,{}_{\sim}$  The power dissipation is limited by  $175\,{}^{\circ}\!\mathrm{C}$  junction temperature

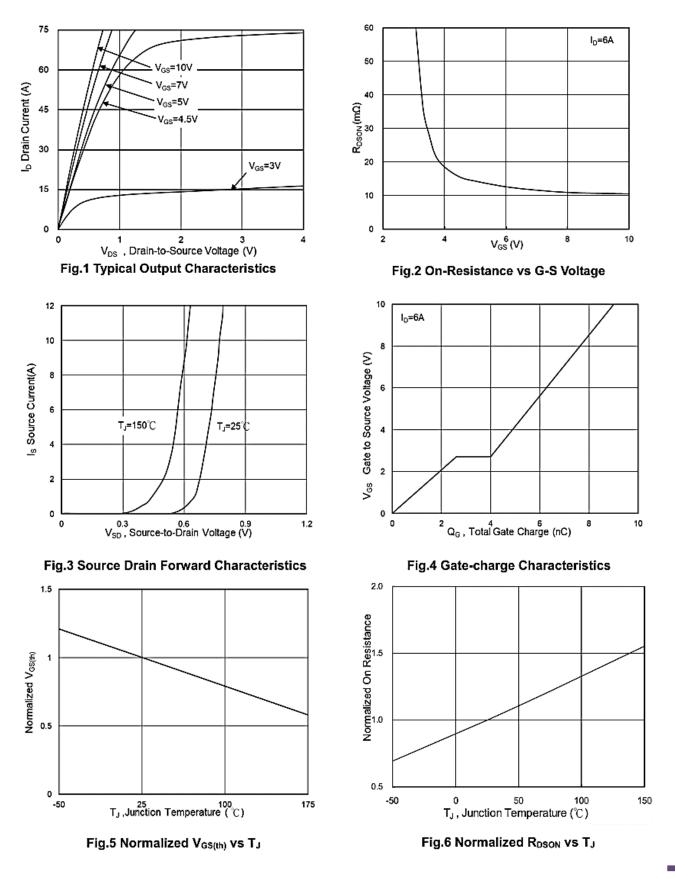
 $4_{\text{N}}$  The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

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### **30V N-Channel Enhancement Mode MOSFET**

### **Typical Characteristics**



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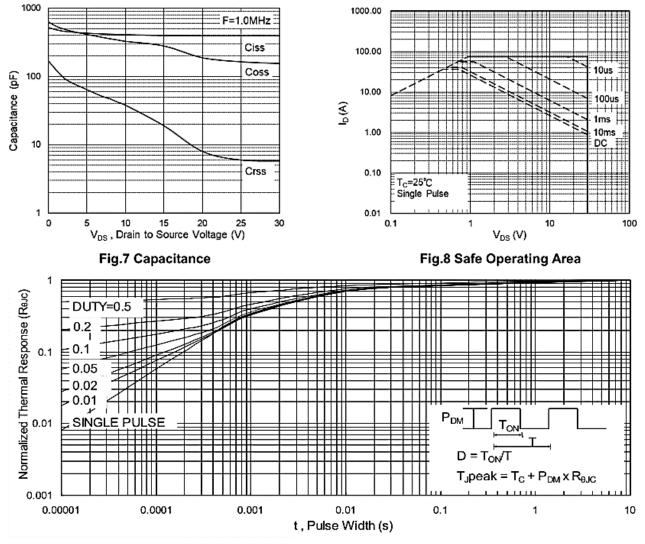


Fig.9 Normalized Maximum Transient Thermal Impedance

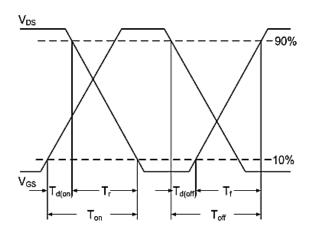


Fig.10 Switching Time Waveform

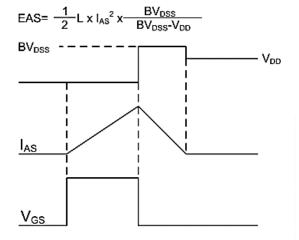


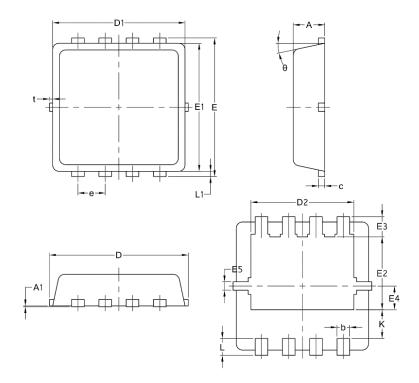
Fig.11 Unclamped Inductive Waveform

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### Package Mechanical Data-DFN3\*3-8L-JQ Single



	Common mm		
Symbol			
	Mim	Nom	Max
А	0.70	0.75	0.85
A1	/	/	0.05
b	0.20	0.30	0.40
С	0.10	0.152	0.25
D	3.15	3.30	3.45
D1	3.00	3.15	3.25
D2	2.29	2.45	2.65
E	3.15	3.30	3.45
E1	2.90	3.05	3.20
E2	1.54	1.74	1.94
E3	0.28	0.48	0.65
E4	0.37	0.57	0.77
E5	0.10	0.20	0.30
е	0.60	0.65	0.70
К	0.59	0.69	0.89
L	0.30	0.40	0.50
L1	0.06	0.125	0.20
t	0	0.075	0.13
Φ	10	12	14

С



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### **30V N-Channel Enhancement Mode MOSFET**

Edition	Date	Change
Rve1.0	2021/8/10	Initial release

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